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Key indicators

Single-crystal X-ray study T = 294 K Mean σ (C–C) = 0.003 Å Disorder in main residue R factor = 0.037 wR factor = 0.104 Data-to-parameter ratio = 12.9

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

N-(2-Fluorophenyl)phthalimide

In the title compound, $C_{14}H_8FNO_2$, the dihedral angle between the two planar ring systems is 59.95 (4)°.

Comment

The crystal structure of the title compound, (I), has been determined in order to elucidate the molecular conformation. The dihedral angle between the benzene ring and the phthalimide plane is $59.95 (4)^{\circ}$.



Experimental

Compound (I) was prepared from phthalic anhydride and 2-fluoroaniline (Barchin *et al.*, 2002). An acetic acid solution of phthalic anhydride (14.8 g, 100 mmol) and 2-fluoroaniline (11.1 g, 100 mmol) was refluxed overnight, and then filtered. The crude product was washed with water three times, and dried. The compound (I) was recrystallized from ethyl acetate (m.p. 465 K).

Crystal data	
C ₁₄ H ₈ FNO ₂	Mo <i>K</i> α radiation
$M_r = 241.21$	Cell parameters from 1794
Orthorhombic, Pbca	reflections
a = 11.622 (3) Å	$\theta = 2.4-22.5^{\circ}$
b = 7.8368 (16) Å	$\mu = 0.11 \text{ mm}^{-1}$
c = 24.017 (5) Å	T = 294 (2) K
V = 2187.5 (8) Å ³	Prism, white
Z = 8	$0.26 \times 0.20 \times 0.16 \text{ mm}$
$D_x = 1.465 \text{ Mg m}^{-3}$	
Data collection	
Bruker SMART CCD area-detector	2240 independent reflections
diffractometer	1169 reflections with $I > 2\sigma(I)$
φ and ω scans	$R_{\rm int} = 0.066$
Absorption correction: multi-scan	$\theta_{\rm max} = 26.4^{\circ}$
(SADABS; Sheldrick, 2002)	$h = -13 \rightarrow 14$
$T_{\min} = 0.967, T_{\max} = 0.983$	$k = -7 \rightarrow 9$
11486 measured reflections	$l = -29 \rightarrow 29$

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Refinement

Refinement on F^2	$w = 1/[\sigma^2(F_o^2) + (0.0411P)^2]$
$R[F^2 > 2\sigma(F^2)] = 0.037$	+ 0.2748P]
$wR(F^2) = 0.104$	where $P = (F_0^2 + 2F_c^2)/3$
S = 0.99	$(\Delta/\sigma)_{\rm max} = 0.001$
2240 reflections	$\Delta \rho_{\rm max} = 0.13 \text{ e } \text{\AA}^{-3}$
174 parameters	$\Delta \rho_{\rm min} = -0.12 \text{ e } \text{\AA}^{-3}$
H-atom parameters constrained	Extinction correction: SHELXTL
	Extinction coefficient: 0.0218 (14)

 Table 1

 Selected geometric parameters (Å, °).

1.372 (3) 1.475 (2)
1 475 (2)
1.4/3 (3)
1.382 (3)
1.489 (3)
C12 120.9 (2)
N1 125.17 (18)
C13 129.19 (19)
213 105.64 (16)

The F atom is disordered over two ortho positions with refined occupancies of 0.681 (3) and 0.319 (3). All H atoms were initially located in a difference Fourier map. All H atoms were then constrained to an ideal geometry, with C-H distances of 0.93 Å and $U_{\rm iso}({\rm H}) = 1.2U_{\rm eq}({\rm C})$.

Data collection: *SMART* (Bruker, 1997); cell refinement: *SAINT* (Bruker, 1997); data reduction: *SAINT*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL* (Bruker, 1997); software used to prepare material for publication: *SHELXTL*.

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Figure 1

The structure of (I), showing the atom-labelling scheme. Displacement ellipsoids are drawn at the 30% probability level.



Figure 2 The crystal packing of (I), viewed along the *b* axis.

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